## Notice of References Cited Application/Control No. 10/604,565 Applicant(s)/Patent Under Reexamination CHENG ET AL. Examiner Thao P. Le Applicant(s)/Patent Under Reexamination CHENG ET AL. Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,426,254	07-2002	Kudelka et al.	438/246
*.	В	US-2004/0079979	04-2004	Lee et al.	257/301
*	C	US-6,740,555	05-2004	Tews et al.	438/242
*	D	US-5,395,786	03-1995	Hsu et al.	438/248
*	E	US-6,699,794	03-2004	Flietner et al.	438/700
	F	US-2002/0105019	08-2002	Mandelman et al.	257/296
	G	US-			
	Н	US-			
	_	US-		,	
	J	US-			
	К	US-			
	٦	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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	R					•
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	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	S. Wolf and R.N. Tauber, Silicon Processing for the VLSI Era, Vol. 1, Lattice Press, California, pp. 307-308, 323-324
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	w	
	х	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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